

Data sheet	
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BRY39

Programmable unijunction transistor

DESCRIPTION

A planar pnpn trigger device in a TO-72 metal package, intended for use in switching applications such as motor control, oscillators, relay replacement, timers, pulse shapers, etc.

PINNING

Anode gate (ag) connected to case.

PIN	DESCRIPTION
1	cathode
2	cathode gate
3	anode gate
4	anode

ACCESSORIES

56246 (distance disc).

QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{GA}	gate-anode voltage		-	70	V
I_A	anode current	DC value up to $T_{amb} = 25\text{ }^\circ\text{C}$	-	175	mA
T_j	operating junction temperature		-	150	$^\circ\text{C}$
$I_{(P)}$	peak point current	$V_S = 10\text{ V}$ $R_G = 10\text{ k}\Omega$	-	0.2	μA

PIN CONFIGURATION

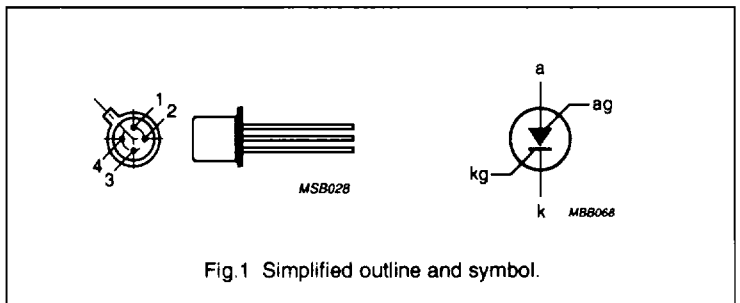


Fig.1 Simplified outline and symbol.

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LIMITING VALUES

In accordance with the Absolute Maximum System (IEC 134).

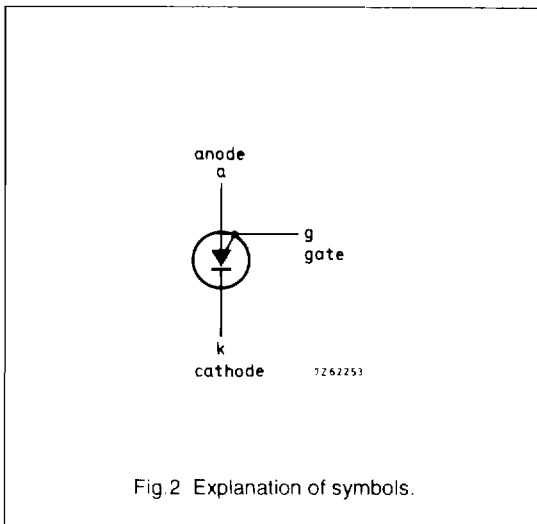
SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{GA}	gate-anode voltage		-	70	V
I_A	anode current	average value up to $T_{amb} = 25\text{ }^{\circ}\text{C}$	-	175	mA
I_{ARM}	repetitive peak anode current	$t_p = 10\text{ }\mu\text{s}$ $\delta = 0.01$	-	2.5	A
I_{ASM}	non-repetitive peak anode current	$t_p = 10\text{ }\mu\text{s}$ $T_J = 150\text{ }^{\circ}\text{C}$	-	3	A
di_A/dt	rate of rise of anode current	up to $I_A = 2.5\text{ A}$	-	20	A/ μs
P_{tot}	total power dissipation	up to $T_{amb} = 25\text{ }^{\circ}\text{C}$	-	275	mW
T_{stg}	storage temperature range		-65	200	$^{\circ}\text{C}$
T_J	junction temperature		-	150	$^{\circ}\text{C}$
T_{amb}	ambient operating temperature range		-65	150	$^{\circ}\text{C}$

THERMAL RESISTANCE

SYMBOL	PARAMETER	MAX.	UNIT
$R_{th\ j-a}$	from junction to ambient in free air	450	K/W

EXPLANATION OF SYMBOLS

For application of the BRY39 as a programmable unijunction transistor, only the anode gate is used. To simplify the symbols, the term gate, instead of anode gate, will be used (see Fig.2).



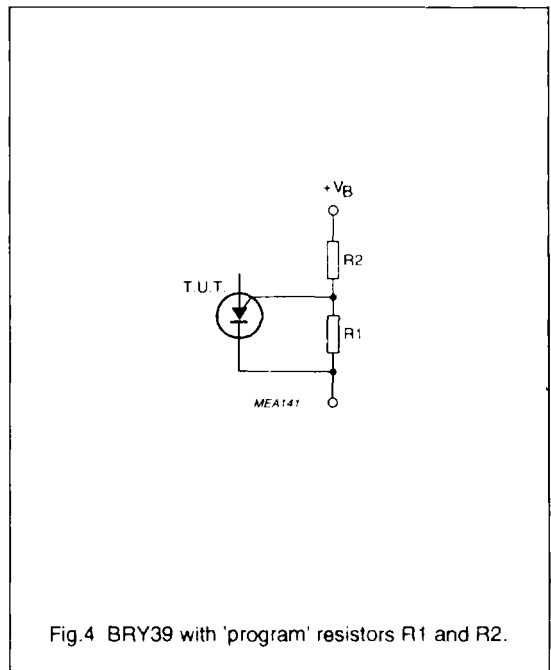
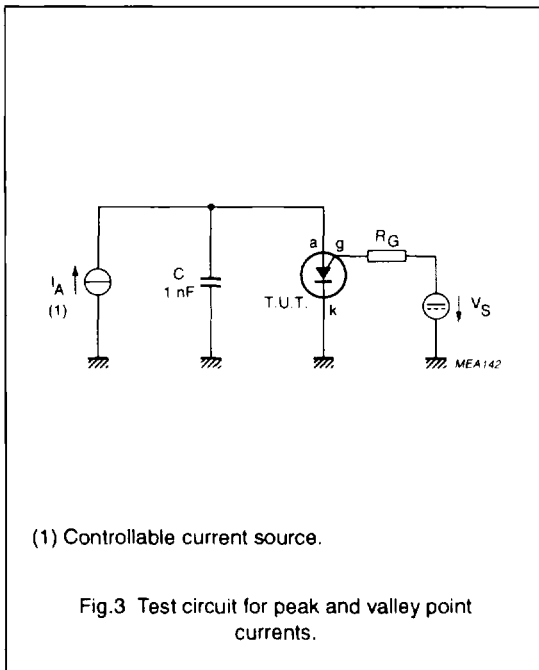
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CHARACTERISTICS

$T_{amb} = 25\text{ }^{\circ}\text{C}$ unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$I_{(P)}$	peak point current (see Figs 3 and 8)	$V_S = 10\text{ V}$ $R_G = 10\text{ k}\Omega$	-	-	0.2	μA
		$V_S = 10\text{ V}$ $R_G = 100\text{ k}\Omega$	-	-	0.06	μA
$I_{(V)}$	valley point current (see Figs 3 and 8)	$V_S = 10\text{ V}$ $R_G = 10\text{ k}\Omega$	-	-	2	μA
		$V_S = 10\text{ V}$ $R_G = 100\text{ k}\Omega$	-	-	1	μA
V_{offset}	offset voltage (for V_P and V_S , see Fig.8)	typical curve $I_A = 0$	-	$V_P - V_S$	-	V
I_{GAO}	gate-anode leakage current	$I_K = 0$ $V_{GA} = 70\text{ V}$	-	-	10	nA
I_{GKS}	gate-cathode leakage current	$V_{AK} = 0$ $V_{KG} = 70\text{ V}$	-	-	100	nA
V_{AK}	anode-cathode voltage	$I_A = 100\text{ mA}$	-	-	1.4	V
V_{OM}	peak output voltage (see Figs 9 and 10)	$V_{AA} = 20\text{ V}$ $C = 10\text{ nF}$	6	-	-	V
t_r	rise time (see Fig.10)	$V_{AA} = 20\text{ V}$ $C = 10\text{ nF}$	-	-	80	ns



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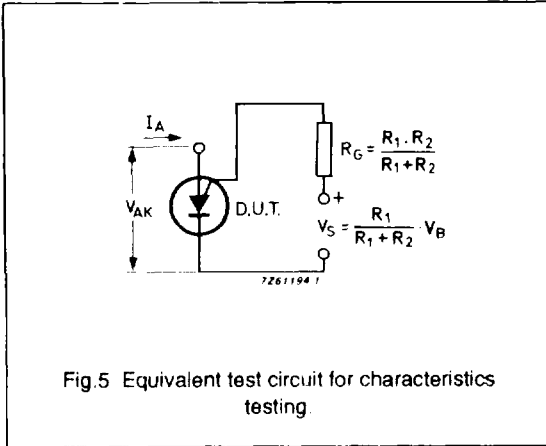


Fig. 5 Equivalent test circuit for characteristics testing.

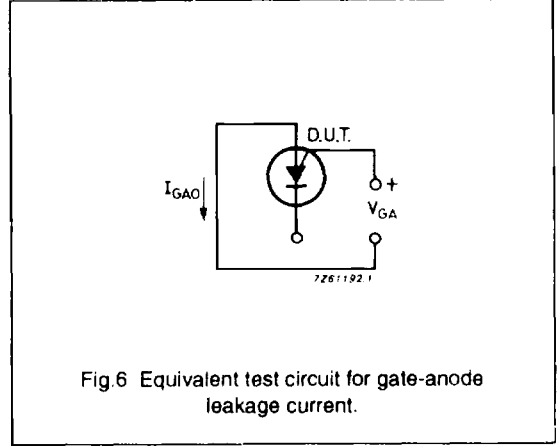


Fig. 6 Equivalent test circuit for gate-anode leakage current.

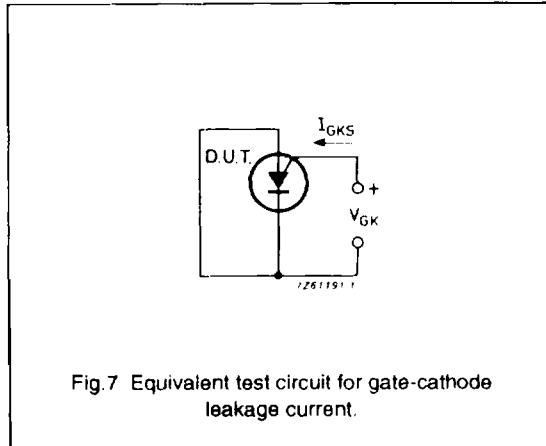


Fig. 7 Equivalent test circuit for gate-cathode leakage current.

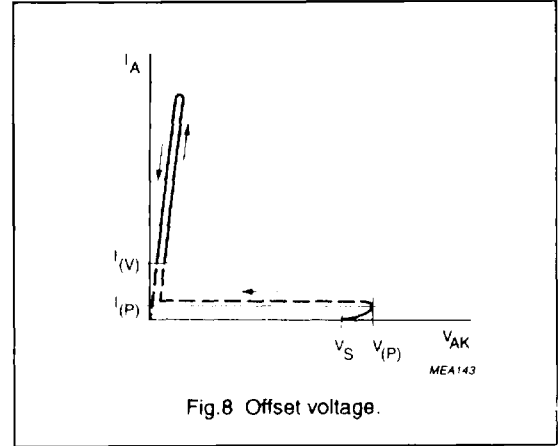


Fig. 8 Offset voltage.

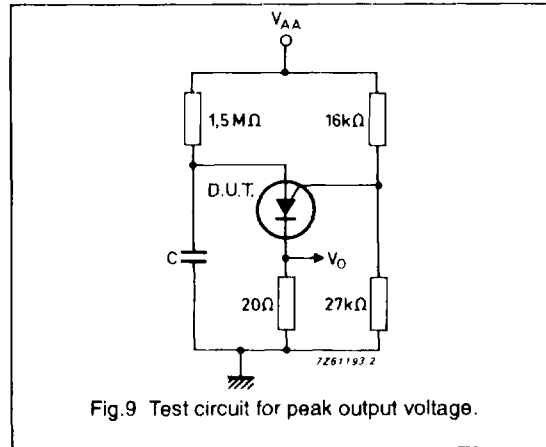


Fig. 9 Test circuit for peak output voltage.

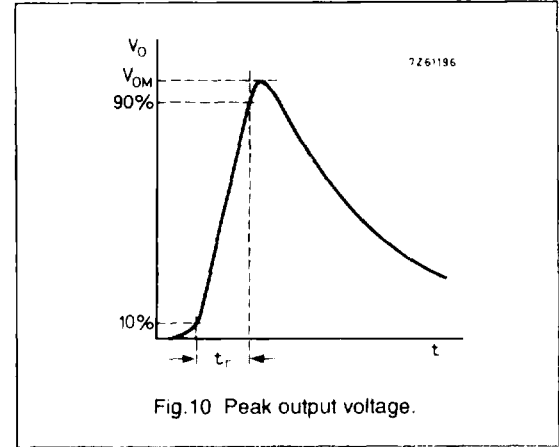
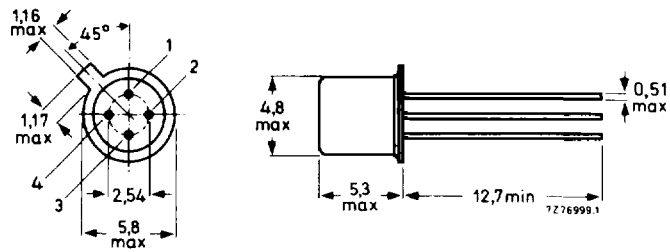


Fig. 10 Peak output voltage.

**Programmable unijunction
transistor****BRY39****PACKAGE OUTLINE**

Dimensions in mm.

Fig.11 TO-72.